

Notice of References Cited	Application/Control No. 08/840,947	Applicant(s)/Patent Under Reexamination LIU, EDWARD W.	
	Examiner DINH T. LE	Art Unit 2816	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,038,215	08-1991	HADFIELD	358/150
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	P					-
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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